## Application/Control No. O9/783,254 Examiner Hieu Phan Applicant(s)/Patent Under Reexamination SIRHAN ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,283,257	02-1994	Gregory et al.	514/458
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	К	US-			
	L	US-			
	М	US-			

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## **NON-PATENT DOCUMENTS**

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